

ECM'08

Electron Cloud Mitigation 2008 (CARE-HHH Mini-Workshop)

20 – 21 November 2008, CERN

MEST

Multipactor Effect Simulation Tool

Work done under ESA AO 4025:

Surface Treatment and Coating for the Reduction of Multipactor
and Passive Intermodulation (PIM) Effects in RF Components

by

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Overview

For detecting multipactor in infinite parallel plate geometry

Determines initial multipactor susceptibility

For studying influence of secondary electron emission properties

Outline

Simplifications and limitations

Complete detailed simulation of electron cloud

Simple detailed realistic Secondary Electron Emission model

Results

Final comments

Electromagnetic field extremely simplified

Infinite parallel plate

Only electric field

Homogeneous every where, only dependent of time

No relativistic effects

$$F_z(t) = e \frac{V_o}{d} \sin(\omega t)$$

No space charge effects

Each electron moves alone in the unperturbed electric field

Each electron trajectory calculated independently

Exact analytical trajectory: emission event \Rightarrow impact event

event: time, position, velocity

No need to calculate trajectories, series of (time, position)

Initial stage or tendency (susceptibility) of multipactor discharge



All the electrons in the cloud are simulated individually

Detailed discrete branching process of multiplications and absorptions

Electron cloud: impact event queue ordered by time to be processed

Electron: object defined by impact event, can relate to emission event

At impact event, new electrons are generated by Secondary Emission

The simulations discrete event approach

- loops along the queue

- advance simulation time

- generate new events

- placing new event orderly in the queue

No resonant conditions are imposed

Simulation procedure

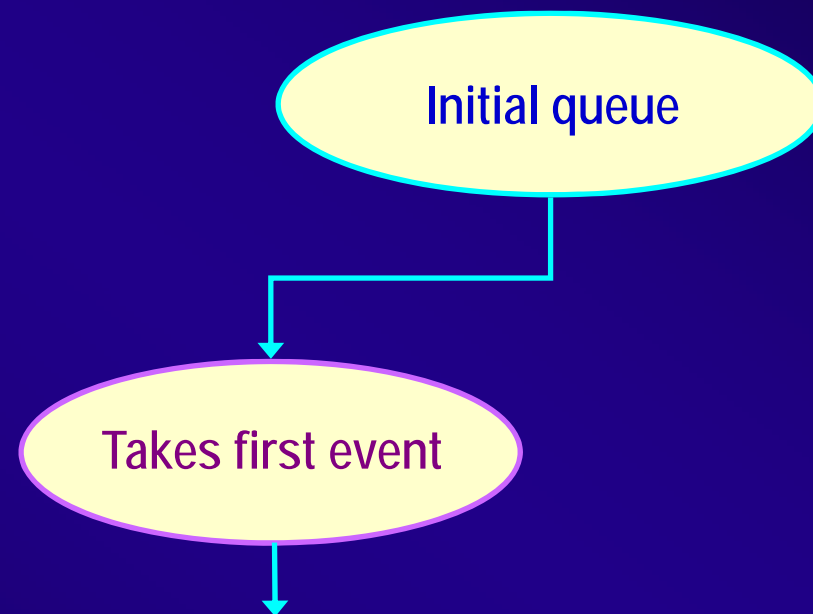
Initial queue: initial electrons, seeding electrons

Random Distribution (time, position, velocity) $\text{number} \leftarrow \text{user}$

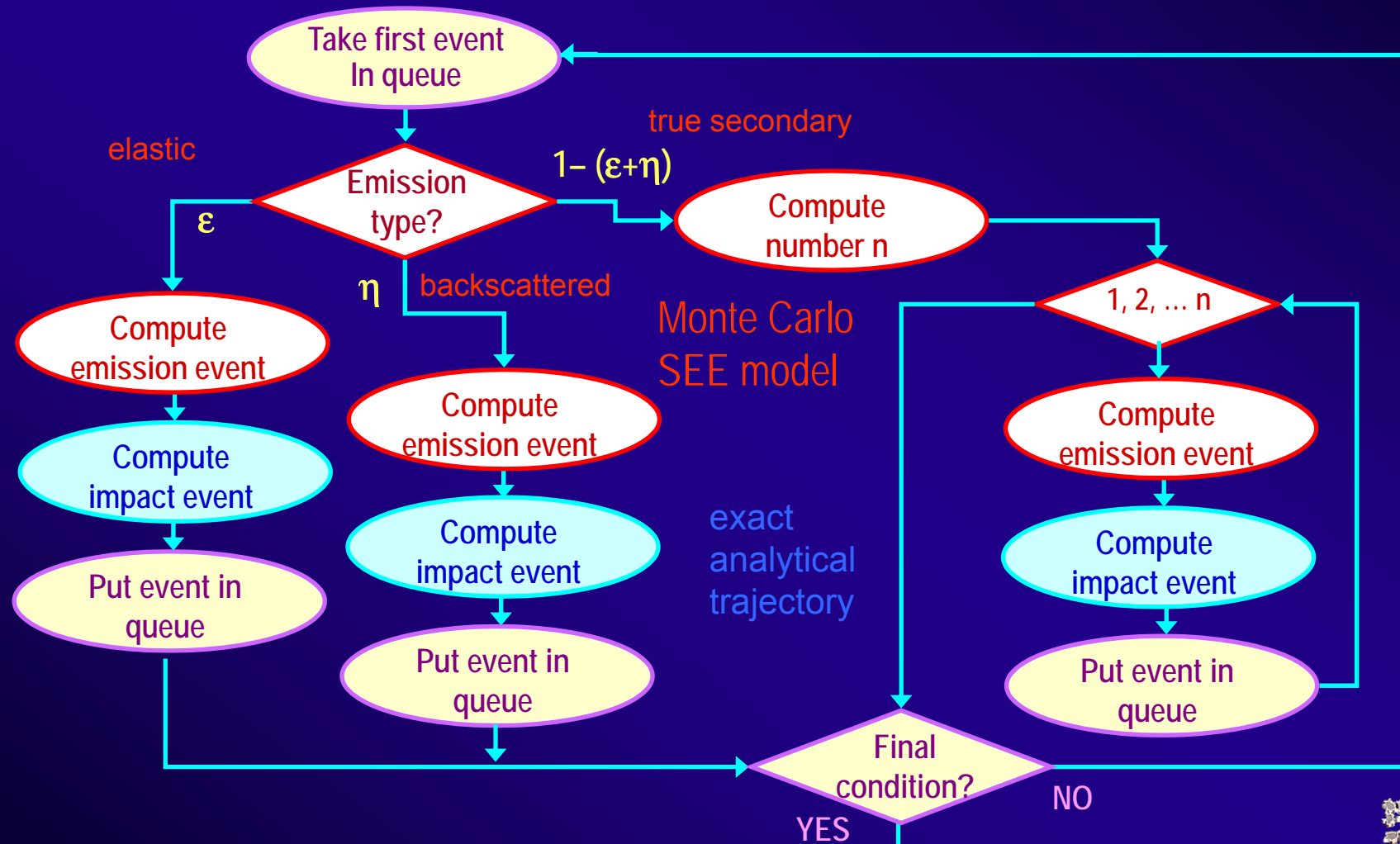
$\text{time} \in \mathcal{D}\text{Uniform}(\text{first period})$

$\text{position} \in \mathcal{D}\text{Uniform}(\text{first plate})$

$\text{velocity} \in \mathcal{D}\text{Normal}(\text{initial velocity})$



Simulation procedure



Final condition: $[(\text{periods} > \text{minimum}) \cap (\text{multipactor} \cup \text{absorption})] \cup (\text{periods} > \text{maximum})$



Monte Carlo Secondary Electron Emission Model

Impact event = (time, position, velocity)

velocity $\Leftrightarrow (E_p, \varphi)$

emission event = (time, position, velocity)

velocity $\Leftrightarrow (E, \theta, \zeta)$

TYPE OF EMISSION EVENT

probability \Leftarrow SEE yield functions

Elastically reflected electron

$$P_e(E_p, \varphi) = \varepsilon(E_p, \varphi)$$

Inelastically backscattered electron

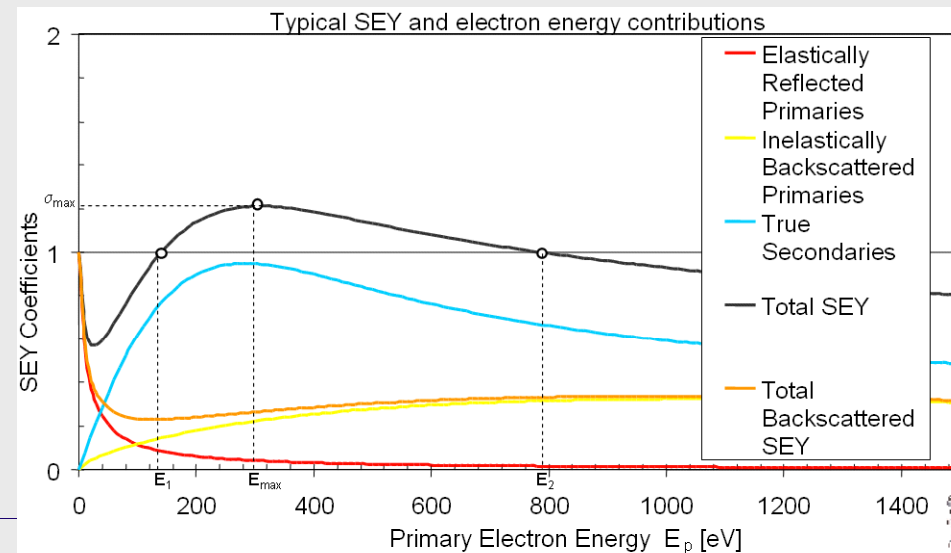
$$P_b(E_p, \varphi) = \eta(E_p, \varphi)$$

True secondary emission of n electrons

$$P_s(E_p, \varphi) = 1 - P_e(E_p, \varphi) - P_b(E_p, \varphi)$$

$n \in \mathcal{D}\text{Poisson}(\text{impact velocity})$

$$\langle n \rangle = \delta(E_p, \varphi) / P_s(E_p, \varphi)$$



Monte Carlo Secondary Electron Emission Model

SEE YIELD FUNCTIONS empirical

$$\varepsilon(E_p, \varphi) = \varepsilon(E_p)^{\cos(\varphi)} \cdot C_2^{1-\cos(\varphi)}$$

$$C_2 = \chi \cdot \frac{\varepsilon(E_p)}{\eta(E_p) + \varepsilon(E_p)}$$

$$\varepsilon(E_p) = \frac{\varepsilon_1}{1 + \frac{E_p}{E_{e_1}}} + \frac{\varepsilon_2}{1 + \frac{E_p}{E_{e_2}}}$$

$$\varepsilon(E_p \approx 0) = 0$$

$$\eta(E_p, \varphi) = \eta(E_p)^{\cos(\varphi)} \cdot C_1^{1-\cos(\varphi)}$$

$$C_1 = \chi \cdot \frac{\eta(E_p)}{\eta(E_p) + \varepsilon(E_p)}$$

$$\eta(E_p) = a \cdot (1 - b \cdot E_p) \cdot E_p^\gamma \cdot \exp\left(-\left(\frac{E_p}{E_b}\right)^\mu\right)$$

$$\delta(E_p, \varphi) = \delta(E_p) \frac{k+1}{k + \cos(\varphi)}$$

$$\delta(E_p) = \delta_m \cdot \frac{s \cdot \frac{E_p}{E_m}}{s - 1 + \left(\frac{E_p}{E_m}\right)^s}$$

constants \leftarrow Material properties

Monte Carlo Secondary Electron Emission Model

EMISSION EVENT: EMISSION ENERGY AND ANGLES

Elastically reflected electron

$$E = E_p, \quad \theta = \varphi, \quad \zeta = 0$$

Inelastically backscattered electron

$$E = E_p \cdot G_b(u) \quad \text{where } u = \in \mathcal{D}\text{Uniform}[0, 1]$$

$$G_b(u) = \alpha^{-1/n_b} \cdot (\arccos(1 - \beta \cdot u))^{1/n_b} \quad \beta = 1 - \cos(\alpha) \quad \alpha = \pi \cdot X_{cb}^{n_b}$$

inverse cumulative probability function, empirical

$$X = G(u) \in \mathcal{D}\text{Distribution(probability } f(X))[0, 1]$$

$$\text{where } f(X) = \frac{dF}{dX} \quad F \equiv G^{-1}$$

$$\theta = \varphi, \quad \zeta = 0$$

constants \leftarrow Material properties



Monte Carlo Secondary Electron Emission Model

EMISSION EVENT: EMISSION ENERGY AND ANGLES

True secondary emission of n electrons

$$E = E_{remain} \cdot G_b(u) \quad G_s(u) = \left(\frac{2}{\pi} \cdot \arctan \left(\sqrt{\tan\left(\frac{\pi}{2} \cdot X_{cs}\right) \cdot \tan\left(\frac{\pi}{2} \cdot u\right)} \right) \right)^{\frac{1}{n_s}}$$

$$E_{remain}(\text{initial}) = E_p$$

$$E_{remain}(\text{next}) = E_{remain} - E \quad \text{ensures conservation of energy, realistic}$$

$$X_{cs}(E_{remain}, \text{material})$$

$$\theta = \arcsin\left(\sqrt{x^2 + y^2}\right) \quad \zeta = \arctan(y/x) \quad (x, y) = \in \mathcal{D}\text{Uniform}(\text{Circle } x^2 + y^2 \leq 1)$$

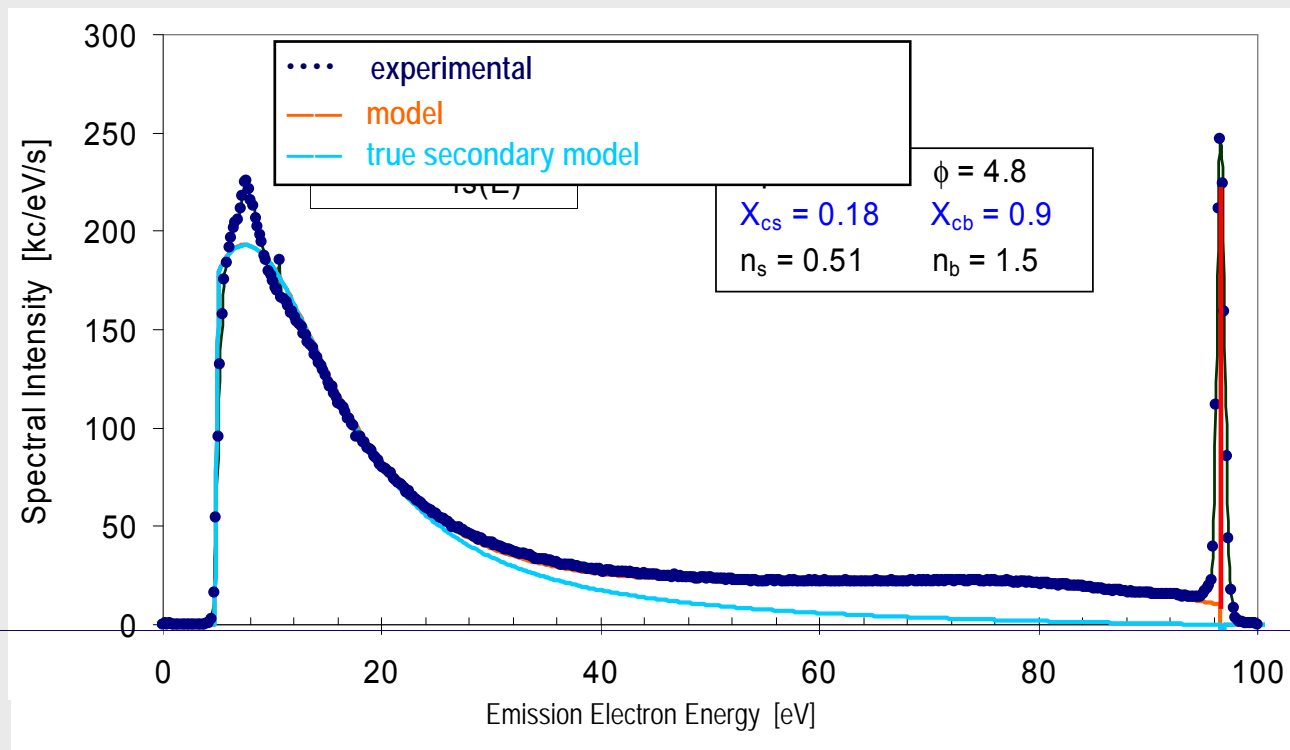
constants \Leftarrow Material properties



Monte Carlo Secondary Electron Emission Model

EMISSION PROBABILITY FUNCTIONS AND EXPERIMENTAL EDC

Clean Cu



MEST main window

alodine.mp - MEST

File View Material Simulation Graphical Outputs Help

Electron Parameters

Initial no. of Electrons: 2000

Initial Electrons Energy (eV) as a normal distribution

Average: 30

Dispersion: 0

Initial Incidence angle (rads) as a normal distribution

Average in $[0, \pi/2]$: 0

0 is normal to the surface

Dispersion: 0

Simulation options

Stop when multipactor

Number of refinements: 1

Simulation

Gap (mm): 2.4

Freq (MHz): 9500

f x d (GHz x mm): 2.3e1

V (Volts): 2040

Time (ns): 933.586473100

Number of Electrons: 2338

Experiment Progress: [Progress bar]

Accuracy: 160.0000 Volts, 0.2000 GHz x mm

Material: Alodine (E1 = 63.7 eV; sey max = 1.401, Emax = 212.5 eV; E2 = 965.8 eV)

Geometry

Type: Infinite Parallel Plates

Gap

Height (mm)

init: 0.2 final: 3 increment: 0.2

Width (mm): 5

Length (mm): 5

Electromagnetic Field

V (Volts)

init: 1000 final: 3080 increment: 160

Frequency (MHz): 9500

Final Conditions for Multipactor

Time of Final Event (cycles):

Multipactor condition when: electron's final no. =

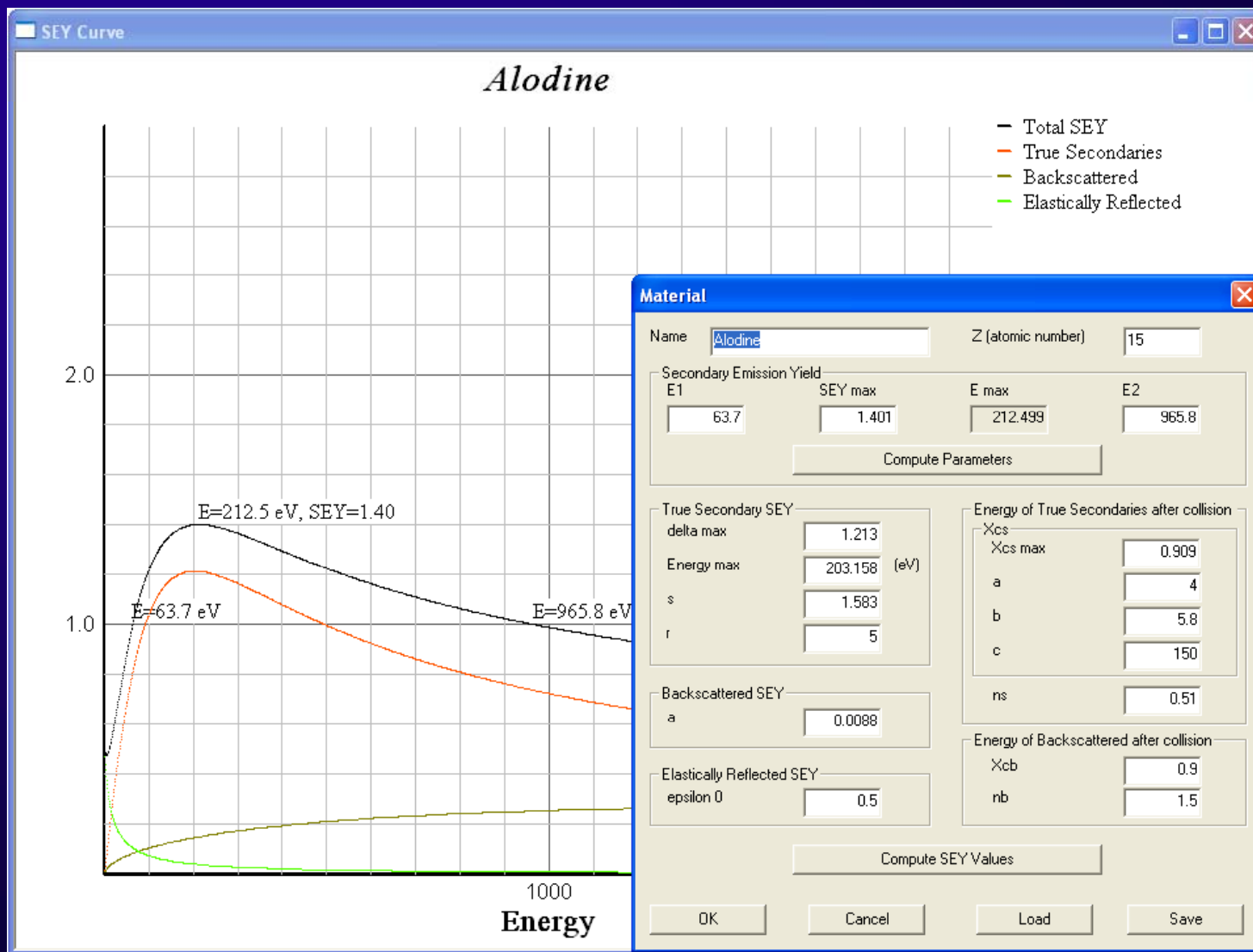
electron's initial no. x 2.7

gap (mm)	frequency (MHz)	fxd (GHz mm)	voltage (V)	impedance (A)
0.1125	9500	1.1e0	90	unknown
0.125	9500	1.2e0	90	unknown
0.1375	9500	1.3e0	90	unknown
0.1125	9500	1.1e0	95	unknown
0.15	9500	1.4e0	95	unknown
0.1	9500	9.5e-1	100	unknown
0.125	9500	1.2e0	100	unknown
0.15	9500	1.4e0	100	unknown
0.1625	9500	1.5e0	100	unknown
0.1	9500	9.5e-1	110	unknown
0.125	9500	1.2e0	110	unknown
0.15	9500	1.4e0	110	unknown
0.175	9500	1.7e0	110	unknown
0.1	9500	9.5e-1	120	unknown
0.125	9500	1.2e0	120	unknown
0.15	9500	1.4e0	120	unknown
0.175	9500	1.7e0	120	unknown
0.0875	9500	8.3e-1	125	unknown
0.1875	9500	1.8e0	125	unknown
0.0875	9500	8.3e-1	130	unknown
0.1	9500	9.5e-1	130	unknown

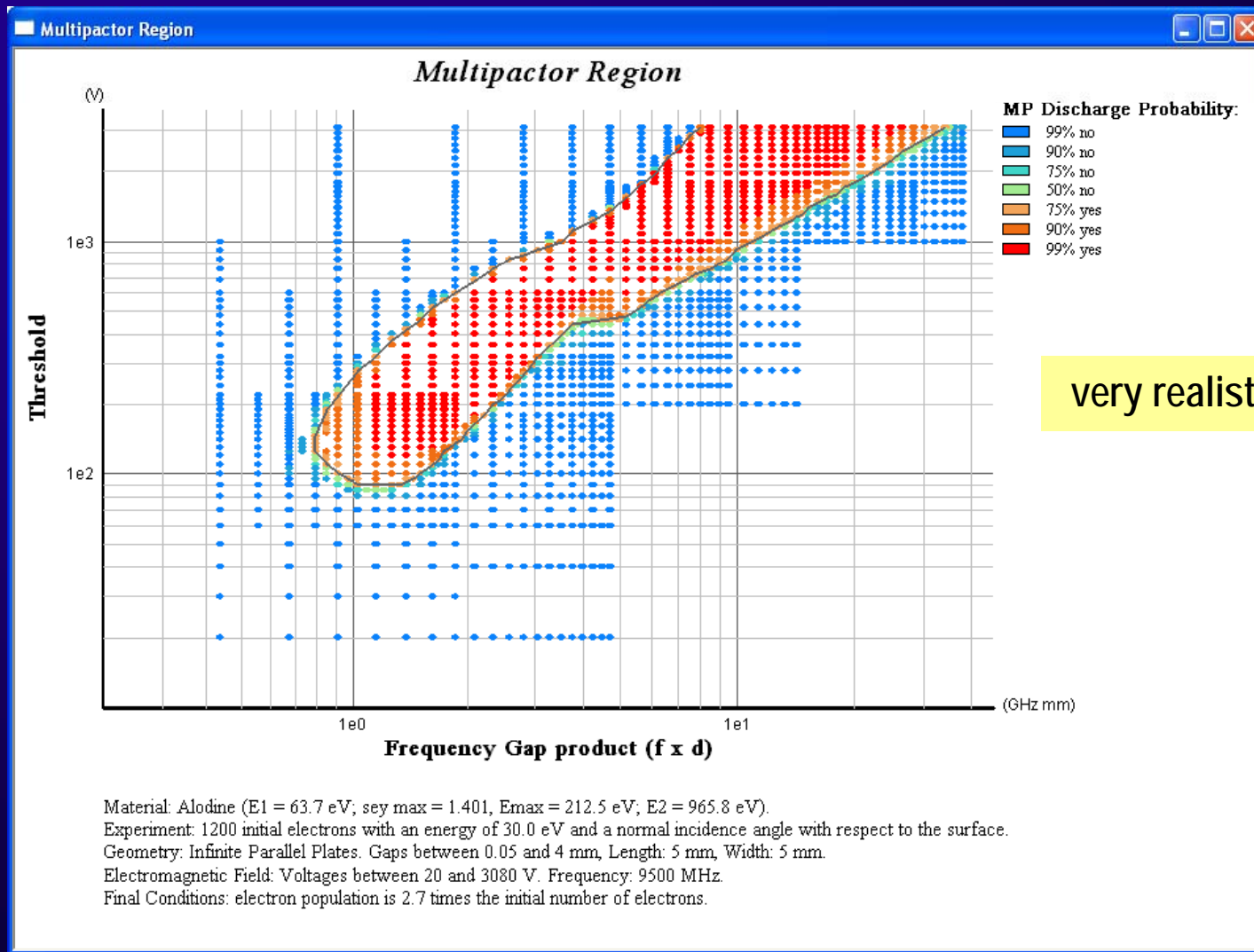
Ready NUM



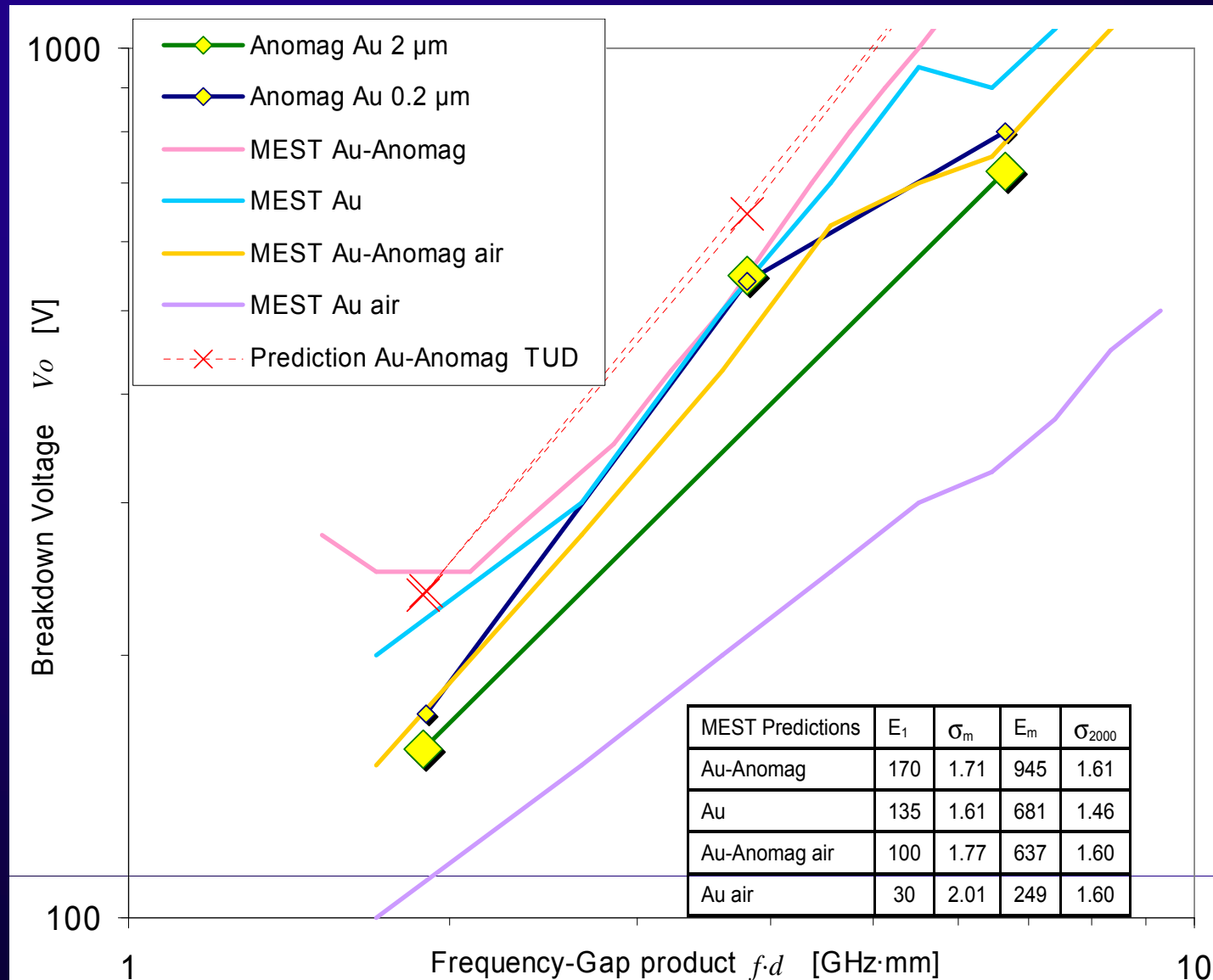
MEST material SEE properties



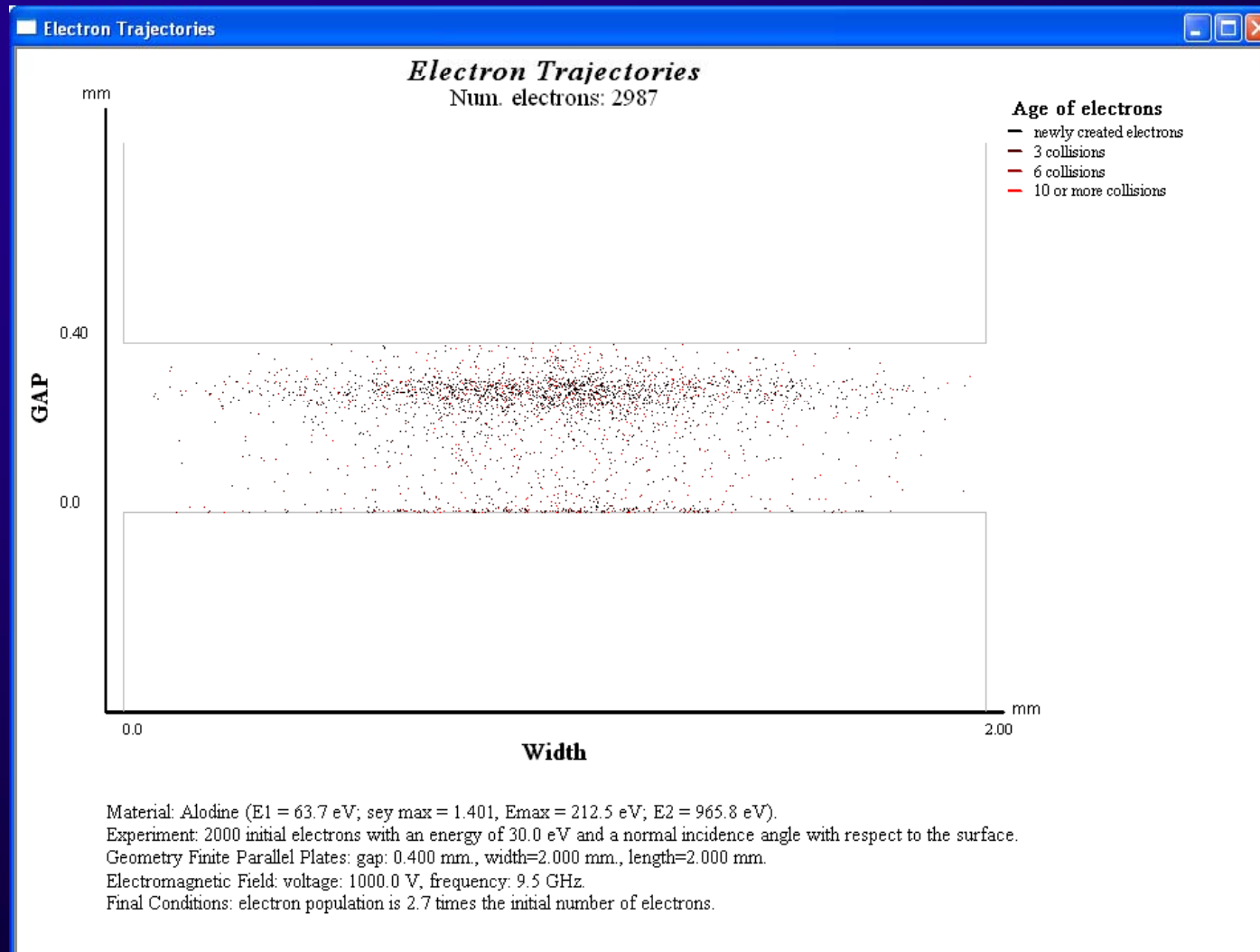
MEST results: multipactor region



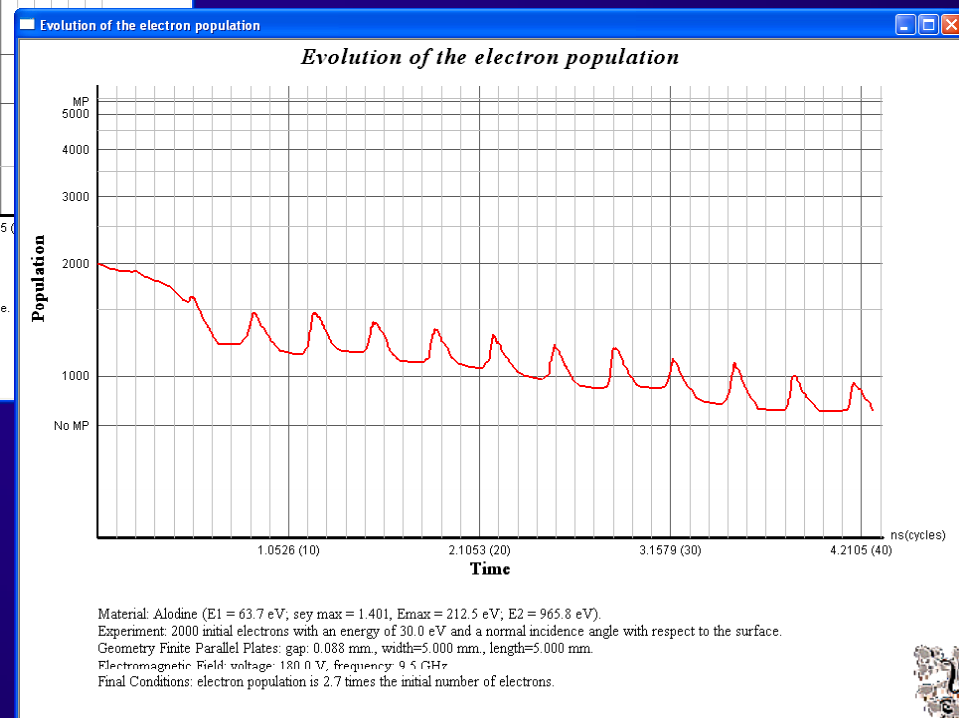
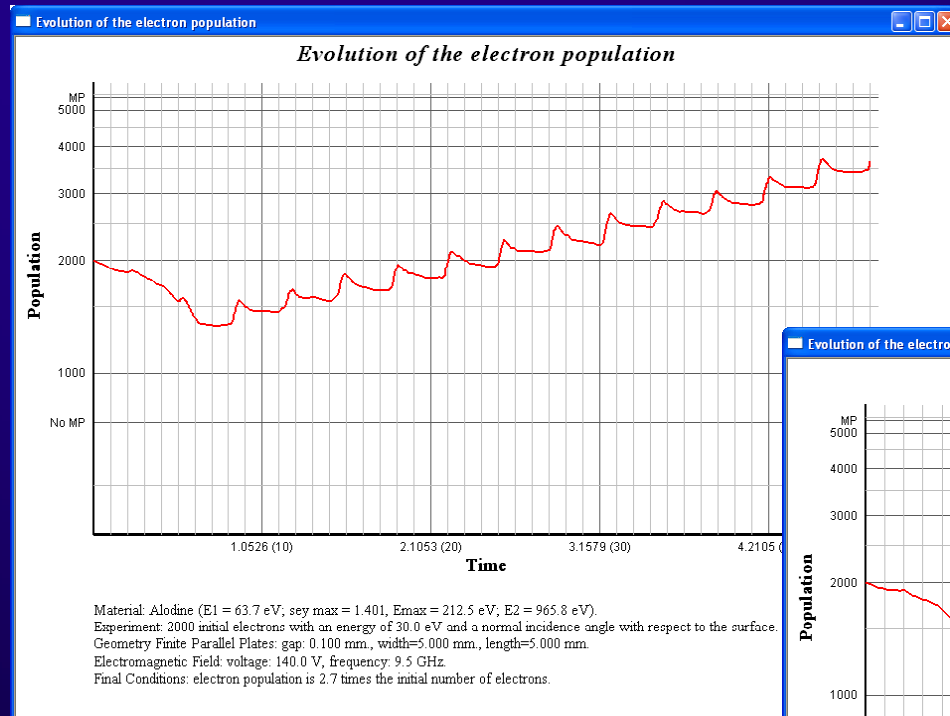
MEST results: multipactor region



MEST results: electron cloud evolution

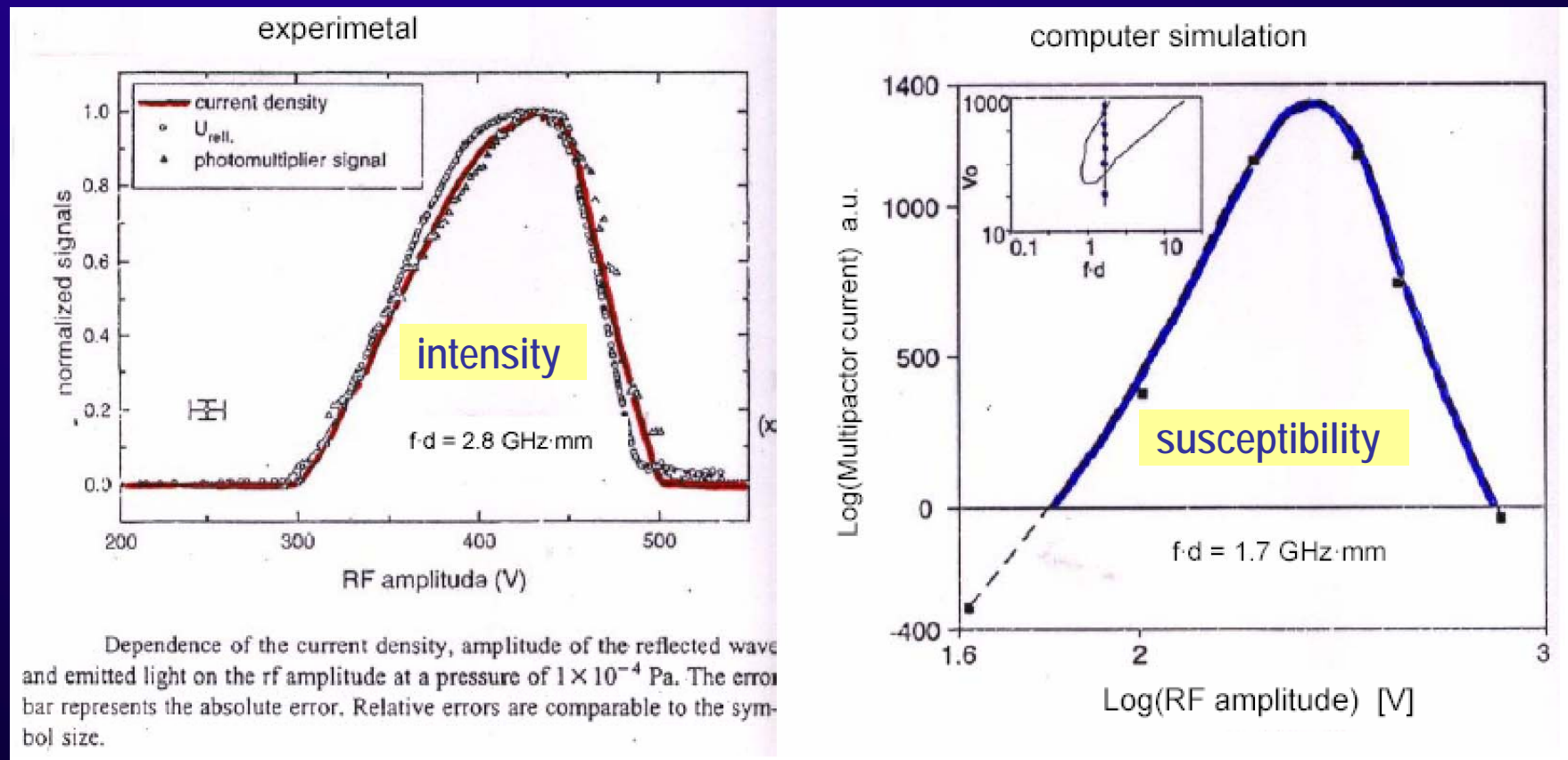


MEST results: electron population evolution



MEST results: electron cloud internal parameters

Precursor of MEST

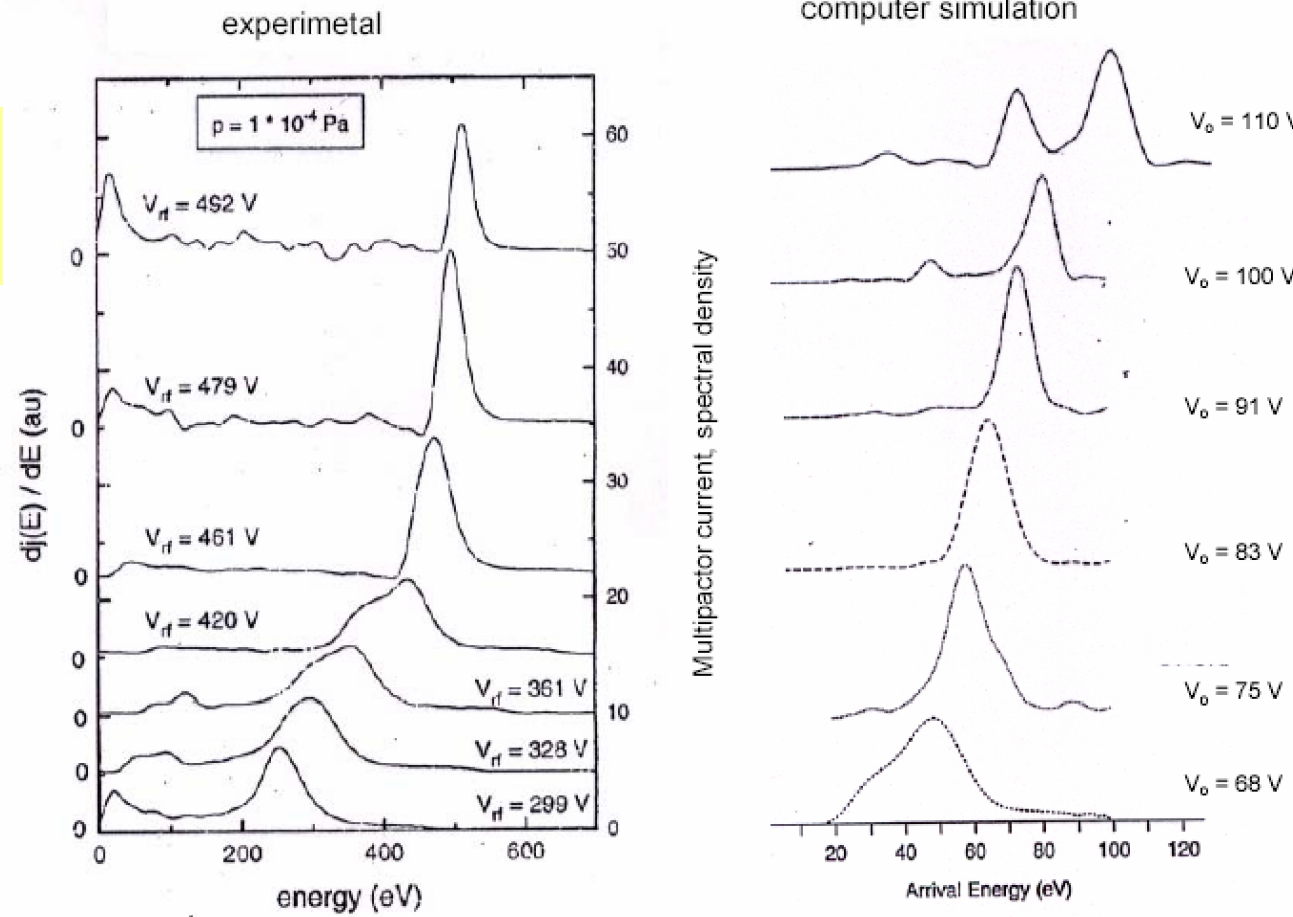


F. Höhn et al, *The transition of a multipactor to a low pressure gas discharge.*

MEST results: electron cloud internal parameters

Precursor of MEST

Bunching of electron energies



Electron energy distribution as a function of the rf amplitude at pressure of 1×10^{-4} Pa.

F. Höhn



Phys. Of Plasmas 4, (10), pp. 940947 (1997)



FINAL COMMENTS

- Multipactor predictions very realistic in spite of strong simplifications in RF field
- Encouragement for using as a tool for testing SEE models and the influence of SEE parameters
- It is still a question how precise should be the SEE model for multipactor predictions
- Are experimental BSE curves important for multipactor prediction?
- Many SEE material parameters are not well known
 - which are “universal”?
 - which are only dependent on Z?
 - which need experimental measurement?
- Is there a need for a materials SEE data base with more than SEY curves?
- Can SEE models explain abnormal SEY curves of rough surfaces?